05NM65-V Power MOSFET

# 0.5A, 650V N-CHANNEL SUPER-JUNCTION MOSFET

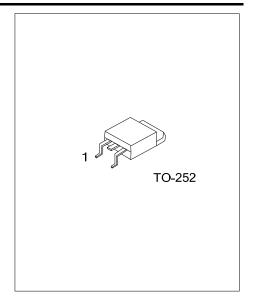
#### **■** DESCRIPTION

The UTC **05NM65-V** is a Super Junction MOSFET Structure and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics.

This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient DC to DC converters and bridge circuits.



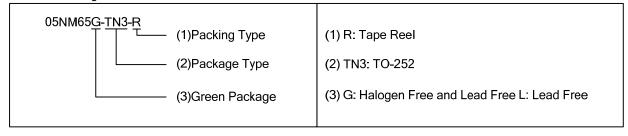
- \*  $R_{DS(on)}$  < 15 $\Omega$  @  $V_{GS}$ =10V,  $I_{D}$ =0.25A
- \* High breakdown voltage



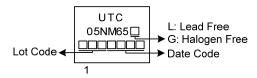
#### **■ ORDERING INFORMATION**

Ordering Number		Doolsons	Pin Assignment			Doolsing	
Lead Free	Halogen Free	Package	1	2	3	Packing	
05NM65L-TN3-R	05NM65G-TN3-R	TO-252	G	D	S	Tape Reel	

Note: Pin Assignment: G: Gate D: Drain S: Source



#### **■** MARKING



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05NM65-V **Power MOSFET** 

## **ABSOLUTE MAXIMUM RATINGS** (T<sub>C</sub>=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		$V_{DSS}$	650	V
Gate-Source Voltage		$V_{GSS}$	±30	V
Drain Current	Continuous	I <sub>D</sub>	0.5	Α
	Pulsed (Note 2)	I <sub>DM</sub>	1.5	Α
Power Dissipation		P <sub>D</sub>	28	W
Junction Temperature		TJ	+150	°C
Storage Temperature Range		T <sub>STG</sub>	-55 ~ +150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

#### **THERMAL DATA**

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	$\theta_{JA}$	110	°C/W	
Junction to Case	$\theta_{ extsf{JC}}$	4.46	°C/W	

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> =25°C, unless otherwise specified)

DADAMETED						1 1	1	
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
OFF CHARACTERISTICS				650	1	I I		
Drain-Source Breakdown Voltage		BV <sub>DSS</sub>	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V				V	
Drain-Source Leakage Current		I <sub>DSS</sub>	V <sub>DS</sub> =650V, V <sub>GS</sub> =0V			10	μΑ	
Gate-Source Leakage Current	Forward	- I <sub>GSS</sub>	$V_{GS}$ =+30V, $V_{DS}$ =0V			+100	nΑ	
Gate-Source Leakage Current	Reverse	1688	$V_{GS}$ =-30V, $V_{DS}$ =0V			-100	nΑ	
ON CHARACTERISTICS		1		1	1	1		
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_D = 250 \mu A$ 1.0			3.0	V	
Static Drain-Source On-State Resistance		R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =0.25A			15	Ω	
DYNAMIC PARAMETERS				•	•			
Input Capacitance	Input Capacitance				37		pF	
Output Capacitance		Coss	$V_{GS}$ =0V, $V_{DS}$ =25V, f=1.0MHz		26		pF	
Reverse Transfer Capacitance	Reverse Transfer Capacitance				3		pF	
SWITCHING PARAMETERS								
Total Gate Charge (Note 1)	Total Gate Charge (Note 1)		1001/1/ 401/1 0.54		5.6		nC	
Gate to Source Charge			$V_{DS}$ =100V, $V_{GS}$ =10V, $I_{D}$ =0.5A,		1.4		nC	
Gate to Drain Charge	<u> </u>		I <sub>D</sub> =1mA (Note 1, 2)		1.4		nC	
Turn-ON Delay Time (Note 1)		t <sub>D(ON)</sub>			3.4		ns	
Rise Time Turn-OFF Delay Time		t <sub>R</sub>	$V_{DS}$ =100V, $V_{GS}$ =10V, $I_{D}$ =0.5A,		4.3		ns	
		t <sub>D(OFF)</sub>	R <sub>G</sub> =25Ω (Note 1, 2)		8		ns	
Fall-Time	•				72.8		ns	
SOURCE- DRAIN DIODE RATING	GS AND CHA	RACTERIST	ics					
Maximum Body-Diode Continuous	Current	I <sub>S</sub>				0.5	Α	
Maximum Body-Diode Pulsed Current		I <sub>SM</sub>				1.5	Α	
Drain-Source Diode Forward Voltage (Note 1)		$V_{SD}$	I <sub>S</sub> =0.5A, V <sub>GS</sub> =0V			1.4	V	
Reverse Recovery Time (Note 1)		t <sub>rr</sub>	V <sub>GS</sub> =0V, I <sub>S</sub> =1.0A,		260		ns	
Reverse Recovery Charge		Q <sub>rr</sub>	dl <sub>F</sub> /dt=100A/µs (Note1)		1420		μC	
Notes: 1. Pulse Test: Pulse width:	≤ 300µs, Duty	cycle≤2%.	WR ON		•			
2. Essentially independent	of operating to	emperature.	18 108					
- '			4年73600					
		A 1	(A) (1) (A)					
		KKK .	CIVILIA					
		: FU	1:1,1					
		* "IN"						
	1	A An.						
Reverse Recovery Time (Note 1)  Reverse Recovery Charge  Q <sub>rr</sub> Q <sub>rr</sub> Q <sub>rr</sub>   V <sub>GS</sub> =0V, I <sub>S</sub> =1.0A,   dI <sub>F</sub> /dt=100A/µs (Note1)  Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%. 2. Essentially independent of operating temperature.						2 of 7		
www.unisonic.com.tw					QW-R205-466.A			

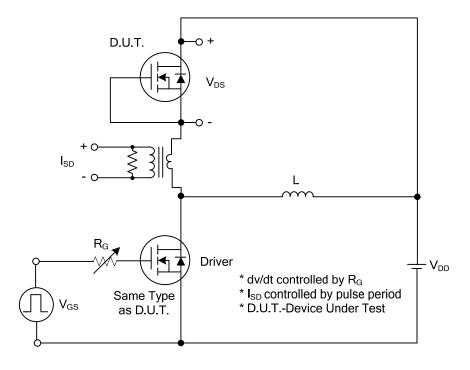


<sup>2.</sup> Repetitive Rating: Pulse width limited by maximum junction temperature.

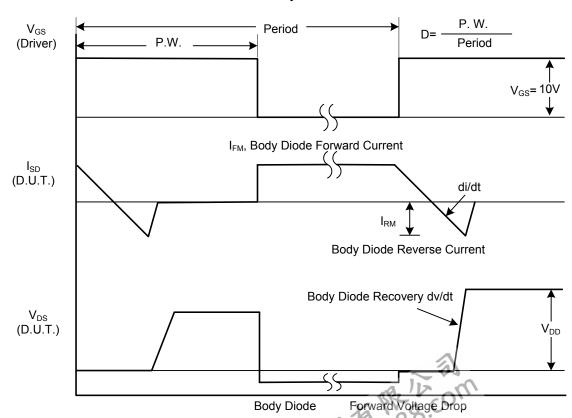
<sup>2.</sup> Essentially independent of operating temperature.

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## ■ TEST CIRCUITS AND WAVEFORMS



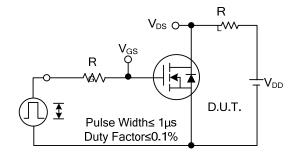
#### Peak Diode Recovery dv/dt Test Circuit



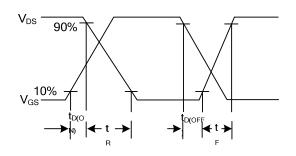
Peak Diode Recovery dwdt Waveforms

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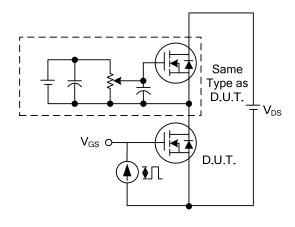
## **TEST CIRCUITS AND WAVEFORMS**



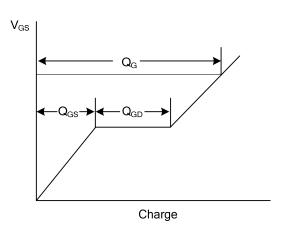
**Switching Test Circuit** 



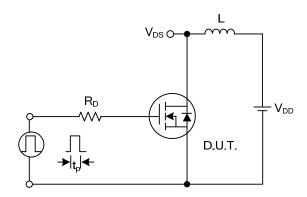
Switching Waveforms



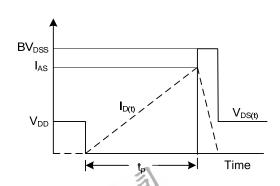
Gate Charge Test Circuit



Gate Charge Waveform

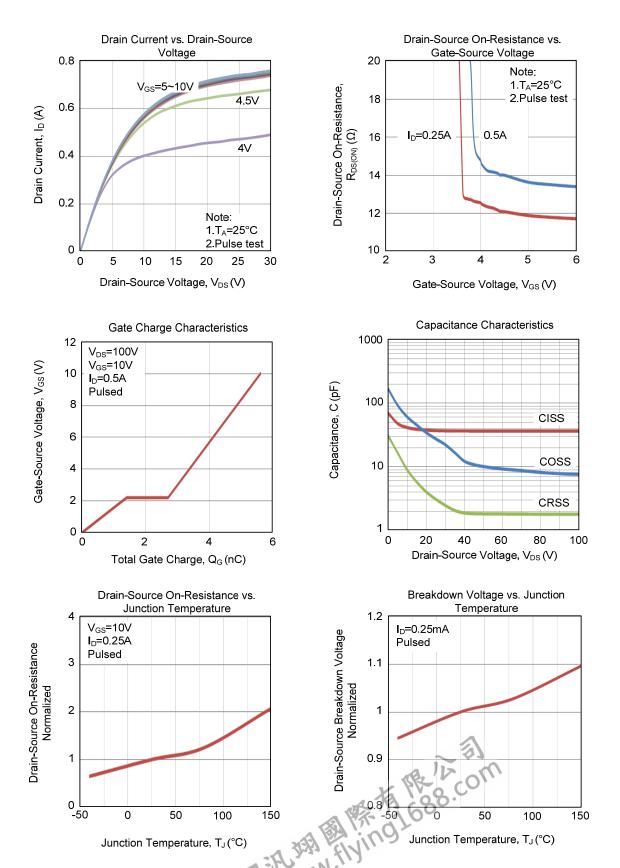


**Unclamped Inductive Switching Test Circuit** 



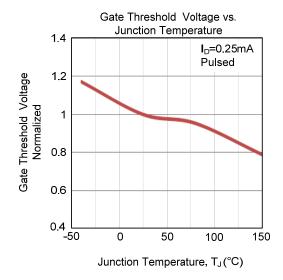
Unclamped inductive Switching Waveforms

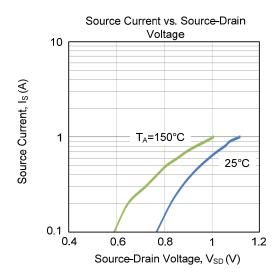
## ■ TYPICAL CHARACTERISTICS

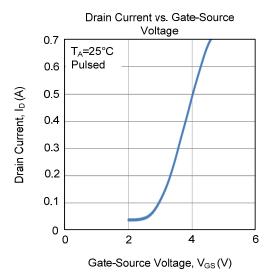


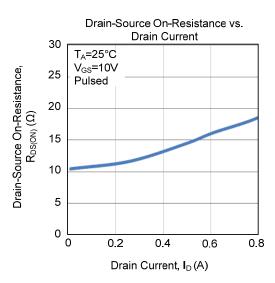
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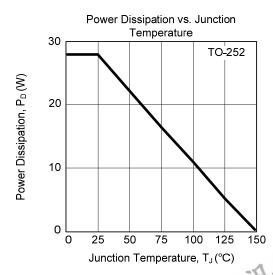
# **■ TYPICAL CHARACTERISTICS (Cont.)**

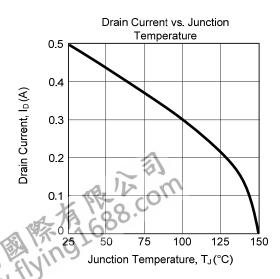




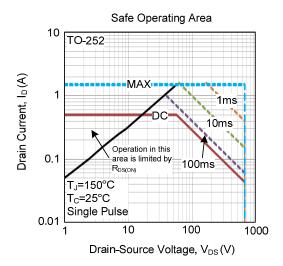








## ■ TYPICAL CHARACTERISTICS (Cont.)



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